TOSHIBA DIODE SILICON EPITAXIAL PLANAR TYPE

155196

ULTRA HIGH SPEED SWITCHING APPLICATION.

• Small Package : SC-59

• Low Forward Voltage : $V_{F(3)} = 0.9V$ (Typ.)

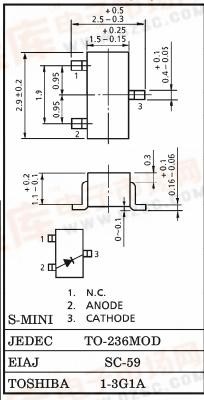
• Fast Reverse Recovery Time: trr=1.6ns (Typ.)

• Small Total Capacitance : C_T=0.9pF (Typ.)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Maximum (Peak) Reverse Voltage	V_{RM}	85	V	
Reverse Voltage	$V_{\mathbf{R}}$	80	V	
Maximum (Peak) Forward Current	I _{FM}	300	mA	
Average Forward Current	I_{O}	100	mA	
Surge Current (10ms)	I_{FSM}	2	Α	
Power Dissipation	P	150	mW	
Junction Temperature	T_{j}	125	°C	
Storage Temperature Range	$ m T_{stg}$	-55~125	°C _	

Unit in mm

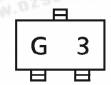


Weight: 0.012g

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Forward Voltage	V _{F (1)}	$I_{\mathbf{F}} = 1 \text{mA}$	_	0.60	_	V
	V _{F (2)}	I _F =10mA	_	0.72	_	
	V _{F (3)}	$I_F = 100 mA$	_	0.90	1.20	
Reverse Current $ \frac{I_{R(1)}}{I_{R(2)}} $	I _{R (1)}	$V_R = 30V$	_====	7	0.1	G.O.
	$V_R=80V$	<u>- P</u>		0.5	μ A	
Total Capacitance	C_{T}	$V_R=0$, $f=1MHz$	7 - Y	0.9	3.0	pF
Reverse Recovery Time	t_{rr}	I _F =10mA (Fig.1)	_	1.6	4.0	ns

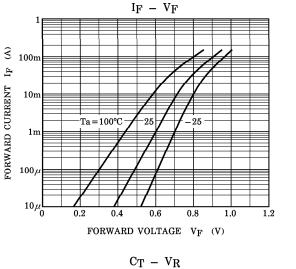
MARKING

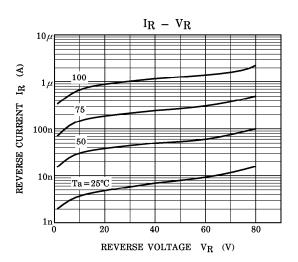


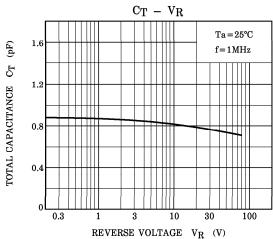
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TOSHIBA 1SS196







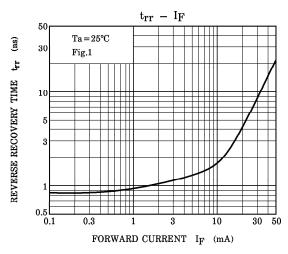
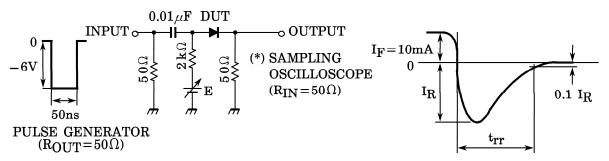


Fig.1 Reverse recovery time (t_{rr}) test circuit

INPUT WAVEFORM

OUTPUT WAVEFORM



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